TOSHIBA TRANSISTOR SILICON NPN EPITAXIAL PLANAR TYPE

M T 3 S 0 7 S

VHF~UHF BAND LOW NOISE AMPLIFIER APPLICATIONS

Low Noise Figure : NF = 1.5 dB

 $(V_{CE} = 3 V, I_{C} = 5 mA, f = 2 GHz)$

 $|S_{21e}|^2 = 9.5 \, dB$ High Gain

 $(V_{CE} = 3 V, I_{C} = 15 \text{ mA}, f = 2 \text{ GHz})$

MAXIMUM RATINGS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	RATING	UNIT
Collector-Base Voltage	v_{CBO}	10	V
Collector-Emitter Voltage	v_{CEO}	5	V
Emitter-Base Voltage	$V_{ m EBO}$	1.5	V
Collector Current	$I_{\mathbf{C}}$	25	mA
Base Current	$I_{\mathbf{B}}$	10	mA
Collector Power Dissipation	$P_{\mathbf{C}}$	100	mW
Junction Temperature	T_j	125	$^{\circ}\mathrm{C}$
Storage Temperature Range	$\mathrm{T_{stg}}$	-55~125	$^{\circ}\mathrm{C}$

1.6 ± 0.2 0.8 ± 0.1 1. BASE 2. EMITTER 3. COLLECTOR **JEDEC EIAJ** TOSHIBA 2-2H1A

Unit in mm

MARKING



MICROWAVE CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Transition Frequency	$ m f_{T}$	$V_{\mathrm{CE}} = 3 \mathrm{V}, \; \mathrm{I_{\mathrm{C}}} = 10 \mathrm{mA}$	10	12	_	GHz
Insertion Gain	$ S_{21e} ^2$ (1)	$egin{aligned} \mathrm{V_{CE}} &= 1 \mathrm{V, \ I_{C}} = 5 \mathrm{mA,} \\ \mathrm{f} &= 2 \mathrm{GHz} \end{aligned}$	_	7.5	_	- dB
	$ S_{21e} ^2$ (2)	$egin{aligned} \mathrm{V_{CE}} = 3 \mathrm{V, \ I_{C}} = 15 \mathrm{mA,} \ \mathrm{f} = 2 \mathrm{GHz} \end{aligned}$	6.5	9.5	_	
Noise Figure —	NF (1)	$egin{aligned} \mathrm{V_{CE}} &= 1 \mathrm{V, \ I_{C}} = 5 \mathrm{mA,} \\ \mathrm{f} &= 2 \mathrm{GHz} \end{aligned}$	_	1.6	3	dB
	NF (2)	$V_{CE} = 3 \text{ V}, I_{C} = 5 \text{ mA},$ f = 2 GHz	_	1.5	3	uБ

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TOSHIBA MT3507S

ELECTRICAL CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Collector Cut-off Current	I _{CBO}	$V_{CB} = 5 V, I_E = 0$	_	_	0.1	μ A
Emitter Cut-off Current	I_{EBO}	$V_{EB} = 1 V, I_{C} = 0$	_	_	1	μ A
DC Current Gain	$h_{ extbf{FE}}$	$V_{CE} = 1 \text{ V}, I_{C} = 5 \text{ mA}$	70	_	140	_
Reverse Transfer Capacitance	C_{re}	$V_{CB} = 1 V, I_{E} = 0, f = 1 MHz$ (Note)	_	0.4	0.85	pF

(Note) : C_{re} is measured by 3 terminal method with capacitance bridge.

CAUTION

This device electrostatic sensitivity. Please handle with caution.